

Documents

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Defect management using depth of inspection and the inspection performance metric
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Abstract

Advancement in fundamental engineering aspects of software development enables IT enterprises to develop a more cost effective and better quality product through aptly organized defect management strategies. Inspection continues to be the most effective and efficient technique of defect management. To have an appropriate measurement of the inspection process, the process metric, Depth of Inspection (DI) and the people metric, Inspection Performance Metric (IPM) are introduced. The introduction of these pair of metrics can yield valuable information from a company in relation to the inspection process. ©2011 by Phadke Associates, Inc. All rights reserved.

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